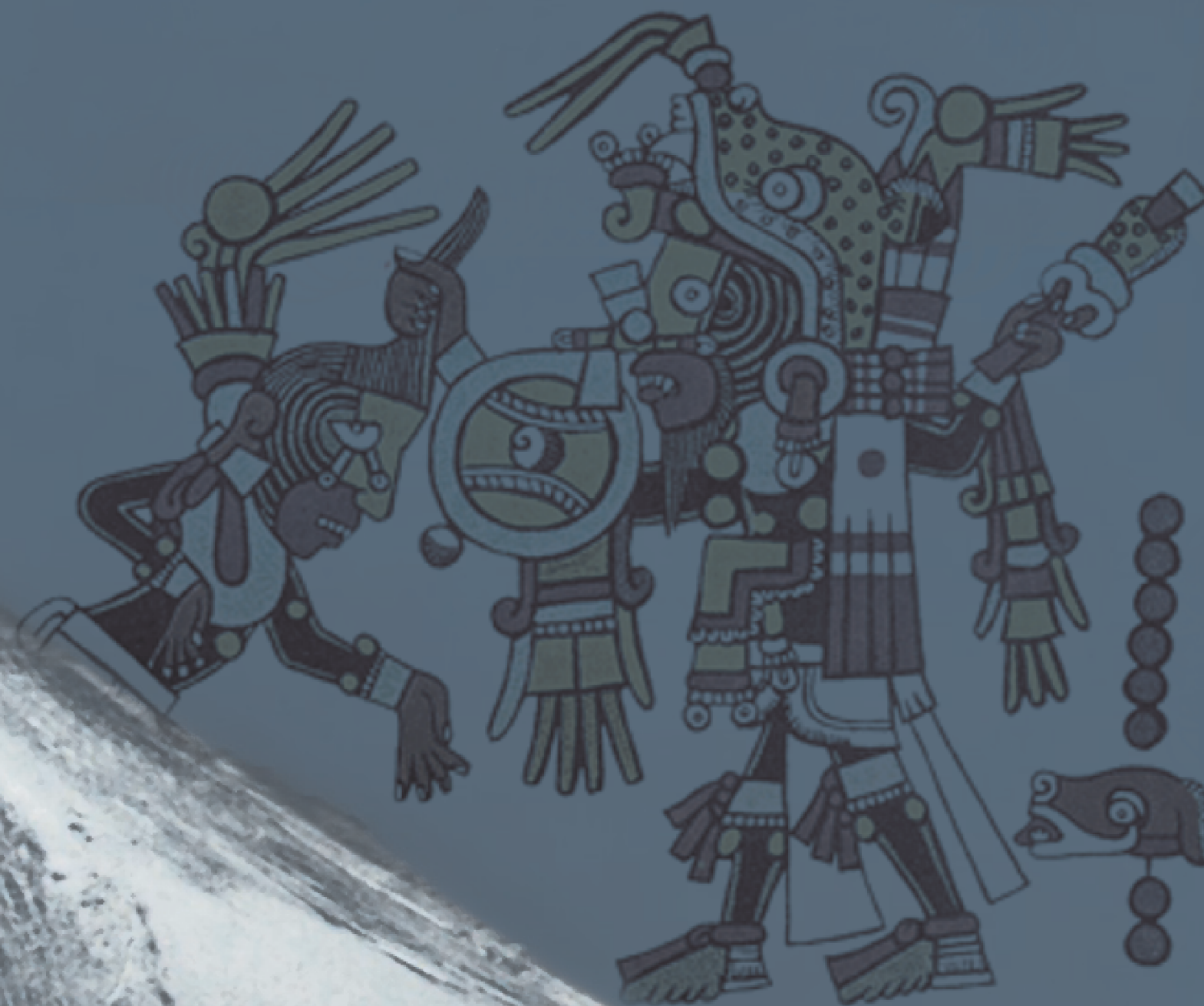# LATW2008

9th IEEE Latin-American Test Workshop
February 17-20, 2008 | Puebla, México

General Chairs V. Champac INAOE, México Y. Zorian Virage Logic Corp.,
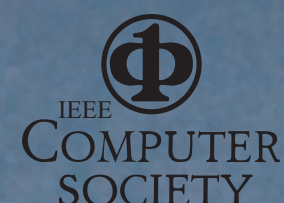**Program Chairs** Marcelo Lubaszewski Raoul Velazco

Submission deadline November 1st, 2007
Notification of acceptance December 10th, 2007
Camera ready January 10th, 2008

http://latw.tttc-events.org/

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LATW2008

9thIEEELatin-AmericanTestWorkshop

Puebla, Mexico **February 17 - 20, 2008**

Call for Papers

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champac@inaoep.mx
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yervant.zorian@viragelogic.com
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The IEEE Latin-American Test Workshop provides an annual forum for test and fault tolerance professionals and technologists from Latin America and all over the world to present and discuss various aspects of system, board and component testing and fault-tolerance with design, manufacturing and field considerations in mind. The best papers presented at the 9th LATW will be invited for submission to the IEEE Design and Test of Computers and Journal of Integrated Circuits and Systems.

Topics of interest include but are not limited to:

- Analog Mixed Signal Test	- Fault Analysis and Diagnosis
- Automatic Test Generation	- Fault Modeling and Simulation
- Board and System Test	- Fault-Tolerance in HW/SW
- Built-In Self-Test	- Fault-Tolerant Architectures
- Defect-Based Test	- Memory Test and Repair
- Dependability	- On-Line Testing
- Design and Synthesis for Testability	- Process Control and Measurements
- Design Verification/Validation	- Radiation Hardening Techniques
- Design for Manufacturability	- System-on-Chip Test
- Economics of Test	- Yield Optimization

Topic Coordinators:

Analog and Mixed-Signal - M. Renovell, LIRMM, France
DfT & BIST - A. Orailoglu, UC San Diego, USA
On-line Test and Fault Tolerance - D. K. Pradhan, University of Bristol, UK
Space Radiation - F. Lima, UFRGS, Brazil
Verification and High Level Test - M. Reorda, Politecnico di Torino, Italy
Software Testing - E. Bezerra, PUCRS, Brazil

Paper Submission Information:

Those interested in presenting recent results at the workshop are invited to submit either an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions **should be done via the workshop webpage: http://latw.tttc-events.org/**. Authors should send papers in the IEEE format with a cover letter indicating the complete mail address, phone/fax numbers and e-mail addresses, the contact person and the presenter. Detailed instructions are available at the workshop webpage. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information please contact one of the Program Co-Chairs.

Marcelo Lubaszewski   luba@ece.ufrgs.br   Raoul Velazco   raoul.velazco@imag.fr

Submission deadline: **November 1st, 2007**
Notification of acceptance: **December 10th, 2007**
Camera Ready: **January 10th, 2008**

LATW2008 will be held in Puebla, Mexico. Puebla is also known as the City of Angels, a World Heritage City, lies 136 km (84 miles) from Mexico City. Puebla, a city of gray hewn stone constructions, is Mexico's fourth largest city. Walking along the streets, you will see marvelous facades with lovely iron balconies, traditional markets and beautiful plazas. Here you will find wonderful crafts, including Talavera pottery, the tree of life figurines, bark paper paintings and unique onyx and marble sculptures. Near Puebla you can visit the Izta-Popo National Park, La Malinche National Park and the Valle de Tehuacan Biosphere Reserve, the largest reserve in the world. From Puebla you can reach interesting ancient places. Among them Cholula Pyramid, Cacaxtla (where you can still admire mural painting), pyramids of Teotihuacan and the site of Monte Alban (Oaxaca).

Sponsored by: IEEE Computer Society Test Technology Technical Council (TTTC)
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